	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
1	BRS	L1	69030	(inspec$4 or detec$4) same ("IC"chip$1 or integrate$1 or wafer$1 or printed near3 circuits)	USPAT	2004/01/25 13:10			0
2	BRS	L2	3404	1 same (void$1 or defect$2)	USPAT	2004/01/25 13:25			0
3	BRS	L3	2	2 same (metallization near10 void$1)	USPAT	2004/01/25 13:12			0
4	BRS	L4	105	2 same (x-ray or x-rays or x-raying or x-rayed)	USPAT	2004/01/25 13:30			0
5	BRS	L5	0	4 and aperture near3 first and aperture near3 second	USPAT	2004/01/25 13:30			0
6	BRS	L6	42	2 and aperture near3 first and aperture near3 second	USPAT	2004/01/25 14:23			0
7	BRS	L7	7	6 and (x-ray or x-rays or x-raying or x-rayed)	USPAT	2004/01/25 13:30			0
8	BRS	L8	3	2 and (aperture near1 array or multi-aperture or plurality near3 apertures) and aperture near3 first and aperture near3 second	USPAT	2004/01/25 14:25			0
9	BRS	L9	38	2 and (aperture near1 array or multi-aperture or plurality near3 apertures)	USPAT	2004/01/25 14:26			0
10	BRS	L10	3	8 and (detector$2 or "CCD")	USPAT	2004/01/25 14:27			0